

**Research Center for Photovoltaics** 

## 連続加速試験によるフレーミング現象の再現

<sup>°</sup>棚橋 紀悟<sup>1</sup>, 櫻井 啓一郎<sup>1</sup>, 塩田 剛史<sup>2</sup>, William Gambogi<sup>3</sup>, Nancy H. Phillips<sup>3</sup>, Kaushik Roy Choudhury<sup>3</sup>, Sergiu Spataru<sup>4</sup>, David C. Miller<sup>5</sup>, Michael Kempe<sup>5</sup>, Michael Owen-Bellini<sup>5</sup>, Peter Hacke<sup>5</sup> <sup>1</sup>産業技術総合研究所, <sup>2</sup>三井化学, <sup>3</sup>DuPont Photovoltaic Solutions, USA, <sup>4</sup>Aalborg University, Denmark, <sup>5</sup>National Renewable Energy Laboratory, USA

## **Field Observations**



## **Summary**

The **"Framing"** (local discoloration along cell edges) was induced by a simple sequential accelerated stress test (consisting of hygrothermal- and UV-stressors: **Panel 1**) applied to the PV modules with high OTR (oxygen transmission rate) backsheet, irrespective of the inclusion of UV-absorber in poly(ethylene-co-vinyl acetate) (EVA) encapsulant.

UV-fluorescence (UV-FL) imaging of the PV modules suggests that the spatially-inhomogeneous degradation of EVA material under UV-irradiating conditions is correlated to this "Framing" indicating an underlying common mechanism. These findings would contribute to the development of test procedures to broadly mimic the actual failures observed in fielded PV.



## Results











The authors wish to thank K. Ogawa, Y. Chiba, and A. Masuda (AIST) for their supports, and the volunteers on Japan team of Photovoltaic Quality Assurance Taskforce (PVQAT) for their helpful discussion. A part of this work was supported by the New Energy and Industrial Technology Development Organization, Japan.

